

# **HAT1047R-VB Datasheet** P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A) <sup>d</sup>	Q <sub>g</sub> (Typ.)			
- 30	0.011 at V <sub>GS</sub> = - 10 V	- 11.6	22 nC			
- 30	0.012 at V <sub>GS</sub> = - 4.5 V	- 10	22 110			

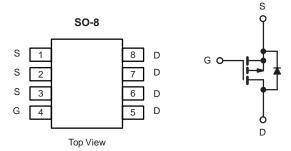
# **FEATURES**

- Halogen-free According to IEC 61249-2-21 **Available**
- Trench Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested





- · Load Switches
  - Notebook PCs
  - Desktop PCs



P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	- 30	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	V
	T <sub>C</sub> = 25 °C		- 11.6	
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	T <sub>C</sub> = 70 °C		- 10.5	
Continuous Diami Curient (1) = 130 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	- 8.7 <sup>a, b</sup>	
	T <sub>A</sub> = 70 °C		- 7.7 <sup>a, b</sup>	
Pulsed Drain Current	I <sub>DM</sub>	- 40	A	
Continuous Course Dunin Die de Course	T <sub>C</sub> = 25 °C	1	- 4.6	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.0 <sup>a, b</sup>	
Avalanche Current	1 04	I <sub>AS</sub>	- 20	
Single-Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	20	mJ
	T <sub>C</sub> = 25 °C		5.6	
Mariana Paran Dissination	T <sub>C</sub> = 70 °C		3.6	W
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.5 <sup>a, b</sup>	vv
	T <sub>A</sub> = 70 °C		1.6 <sup>a, b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	39	50	°C/W	
Maximum Junction-to-Foot	Steady State	R <sub>thJF</sub>	18	22	C/VV	

#### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 85 °C/W. d. Based on  $T_{\rm C}$  = 25 °C.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			- 31		m\//9C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			5.5		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA
Zoro Coto Voltago Proin Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V			- 1	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5	μA
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α
Durin Orania On Otata Basista and	D	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 10 A		0.011		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 7 A		0.012		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 10 A		23		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			1960		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		380		
Reverse Transfer Capacitance	C <sub>rss</sub>			325		
Total Cata Chausa		$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		43	65	nC
Total Gate Charge				22	33	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		6		
Gate-Drain Charge	$Q_{gd}$			11		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.3	1.3	2.5	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			11	22	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, $R_L$ = 3 $\Omega$		13	25	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		32	50	
Fall Time	t <sub>f</sub>			9	18	
Turn-On Delay Time	t <sub>d(on)</sub>			44	70	ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, $R_L$ = 3 $\Omega$		100	160	=
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_{D} \cong -5 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_{g} = 1 \Omega$		28	50	
Fall Time	t <sub>f</sub>			15	30	
<b>Drain-Source Body Diode Characterist</b>	ics					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 4.6	۸
Pulse Diode Forward Current	I <sub>SM</sub>	-			- 50	Α
Body Diode Voltage	V <sub>SD</sub>	$I_S = -2 \text{ A}, V_{GS} = 0 \text{ V}$		- 0.75	- 1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	3 / 63		28	45	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 2 A d1/d+ 400 A/: T 05 00		20	40	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		13		
Reverse Recovery Rise Time	t <sub>b</sub>			15		ns

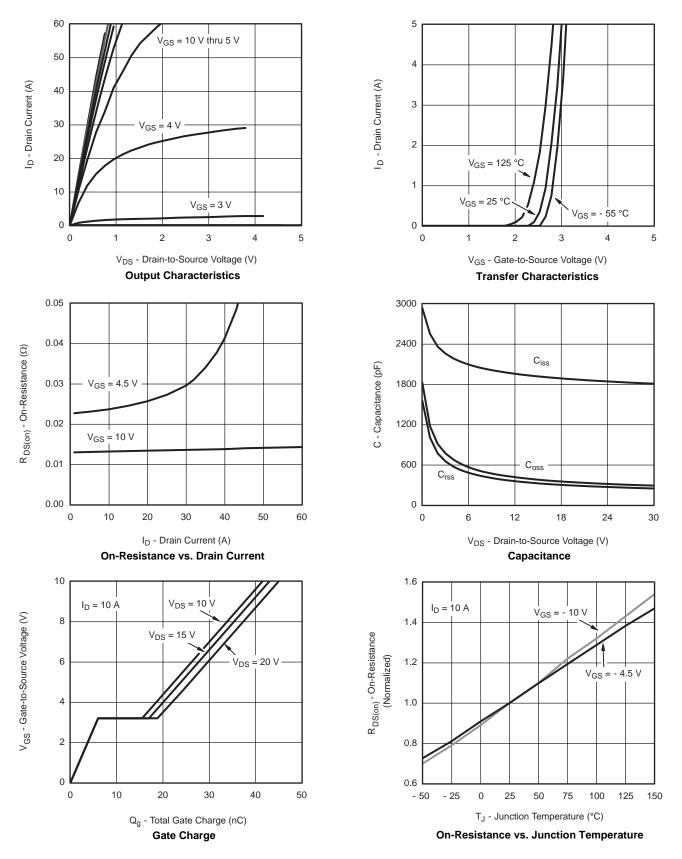
#### Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

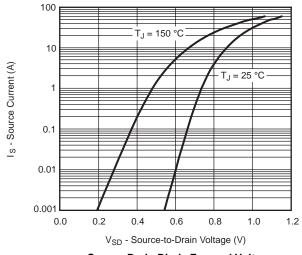
a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$ 

b. Guaranteed by design, not subject to production testing.

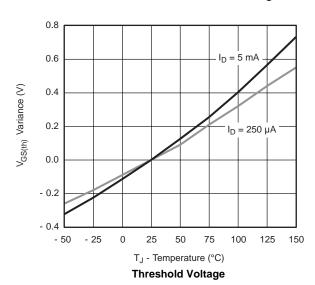






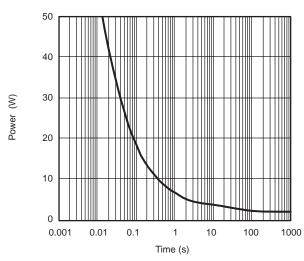


#### Source-Drain Diode Forward Voltage

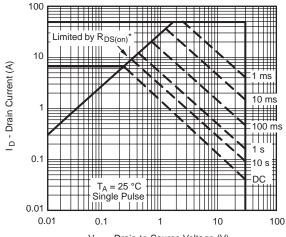


0.10 I<sub>D</sub> = 10 A 0.08 0.06 0.04 0.02 0.00 0 2 4 6 8 10

 $V_{GS}$  - Gate-to-Source Voltage (V) On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

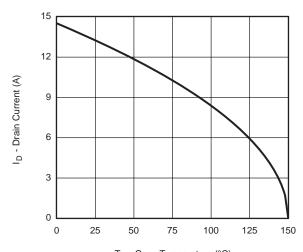


V<sub>DS</sub> - Drain-to-Source Voltage (V)

#### **Safe Operating Area**

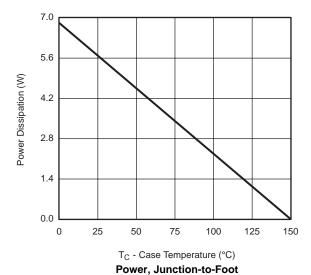
<sup>\*</sup>  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

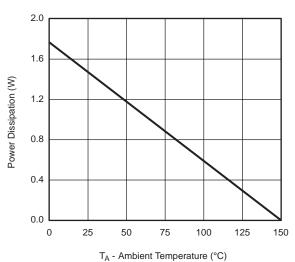




 $T_{\mbox{\scriptsize C}}$  - Case Temperature (°C)

# Current Derating\*

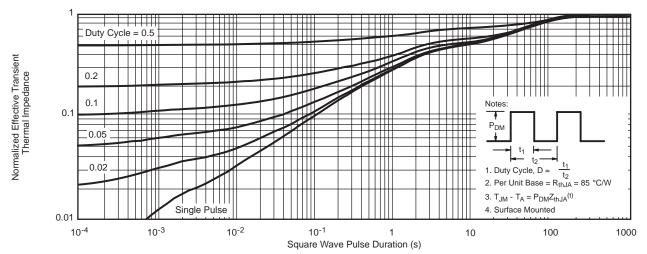




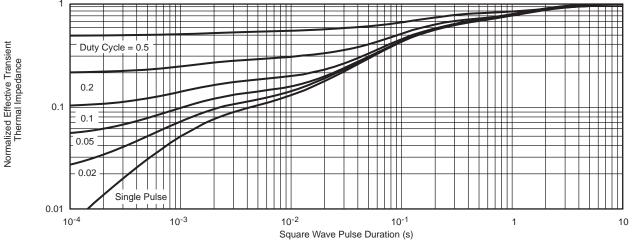
Power Derating, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

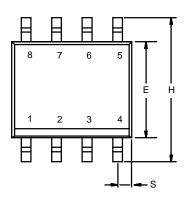


Normalized Thermal Transient Impedance, Junction-to-Foot

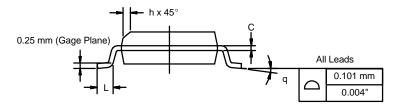
服务热线:400-655-8788 6



**SOIC (NARROW): 8-LEAD**JEDEC Part Number: MS-012







	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A <sub>1</sub>	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev I 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



# **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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